SEMICONDUCTOR®

June 2010 SupreMOSTM

FCH22N60N

N-Channel MOSFET 600V, 22A, 0.165Ω

Features

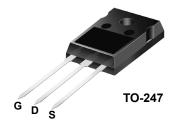
- $R_{DS(on)} = 0.140\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_{D} = 11A$
- BV_{DSS} >650V @ T_J = 150°C
- Ultra Low Gate Charge (Typ. Qg = 45nC)
- · Low Effective Output Capacitance
- 100% Avalanche Tested
- · RoHS Compliant

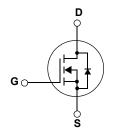


Description

The SupreMOS MOSFET, Fairchild's next generation of high voltage super-junction MOSFETs, employs a deep trench filling process that differentiates it from preceding multi-epi based technologies. By utilizing this advanced technology and precise process control, SupreMOS provides world class Rsp, superior switching performance and ruggedness.

This SupreMOS MOSFET fits the industry's AC-DC SMPS requirements for PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter			Units
V _{DSS}	Drain to Source Voltage			600	V
V _{GSS}	Gate to Source Voltage			±30	V
1	Drain Current	Continuous (T _C = 25°C)		22	Α
Drain Current	Continuous (T _C = 100°C)		13.8	A	
I _{DM}	Drain Current	Pulsed (N	lote 1)	66	Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		672	mJ	
I _{AR}	Avalanche Current		7.3	Α	
E _{AR}	Repetitive Avalanche Energy		2.75	mJ	
dv/dt	Peak Diode Recovery dv/dt	1)	Note 3)	20	V/ns
αν/αι	MOSFET dv/dt			100	V/115
D	Power Dissipation	(T _C = 25°C)		205	W
P_{D}	Power Dissipation	Derate above 25°C		1.64	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

^{*}Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FCH22N60N	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.61	
$R_{\theta CS}$	Thermal Resistance, Case to Heat Sink (Typical)	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	40	

Units

Max.

查询"FCH22N60N"供应商

Package Marking and Ordering Information T_C = 25°C unless otherwise noted

Parameter

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCH22N60N	FCH22N60N	TO247	-	-	30

Test Conditions

Min.

Typ.

Electrical Characteristics

Off Characteristics						
BV _{DSS} Drain to Source Breakd	Drain to Source Proakdown Voltage	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}, T_J = 25^{\circ} \text{C}$	600	-	-	V
	Drain to Source Breakdown voltage	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}, T_J = 150 ^{\circ} \text{C}$	650	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 1mA, Referenced to 25°C	-	0.68	-	V/°C
I _{DSS} Zero Gate Voltage Drain Cui	Zoro Cato Voltago Drain Current	V _{DS} = 480V, V _{GS} = 0V	-	-	10	μА
	Zero Gate Voltage Drain Gurrent	$V_{DS} = 480V, T_J = 125^{\circ}C$	-	-	100	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 50V, V_{DS} = 0V$	-	-	±100	nA

On Characteristics

Symbol

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	3	4.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10V, I _D = 11A	1	0.140	0.165	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 20V, I_{D} = 11A$	-	22	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	1/ 400)/)/ 0)/	-	1950	-	pF
Coss	Output Capacitance	V _{DS} = 100V, V _{GS} = 0V f = 1MHz		75.9	-	pF
C _{rss}	Reverse Transfer Capacitance			3	-	pF
C _{oss}	Output Capacitance	V _{DS} = 380V, V _{GS} = 0V, f = 1MHz		43.2	-	pF
C _{oss} eff.	Effective Output Capacitance	V _{DS} = 0V to 480V, V _{GS} = 0V		196.4	-	pF
Q _{g(tot)}	Total Gate Charge at 10V		-	45	-	nC
Q _{gs}	Gate to Source Gate Charge	V _{DS} = 380V, I _D = 11A,		8.7	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V (Note 4)	-	14.5	-	nC
ESR	Equivalent Series Resistance (G-S)	Drain Open, f=1MHz	-	1	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	16.9	-	ns
t _r	Turn-On Rise Time	$V_{DD} = 380V, I_{D} = 11A$		-	16.7	-	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 4.7\Omega$		-	49	-	ns
t _f	Turn-Off Fall Time		(Note 4)	-	4	-	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	22	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	66	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 11A	-	-	1.2	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 11A	-	350	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	6	-	μС

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 7.3A, R_G = 25 Ω , Starting T_J = 25 $^{\circ}C$
- 3. I_{SD} \leq 22A, di/dt \leq 200A/ μs , V_DD \leq 380V, Starting T_J = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

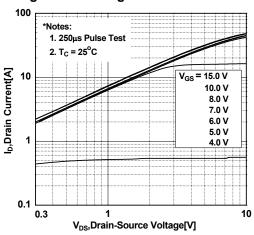


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

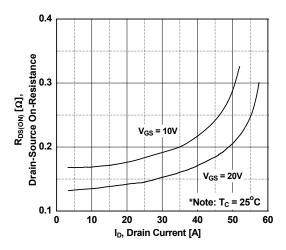


Figure 5. Capacitance Characteristics

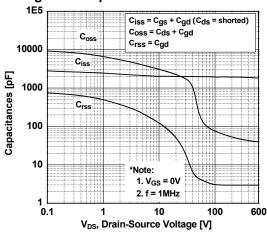


Figure 2. Transfer Characteristics

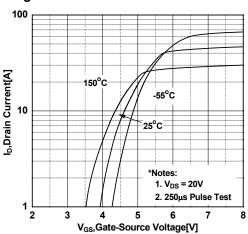


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

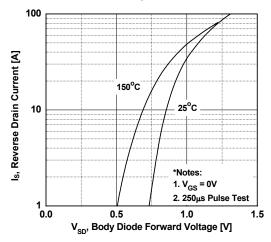
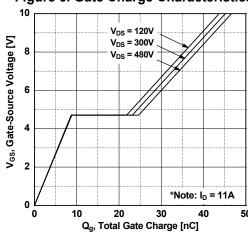


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

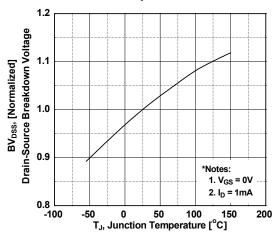


Figure 8. On-Resistance Variation vs. Temperature

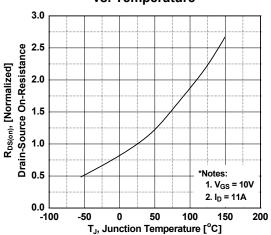


Figure 9. Maximum Safe Operating Area

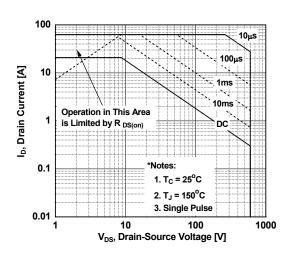


Figure 10. Maximum Drain Current vs. Case Temperature

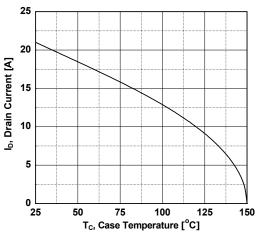
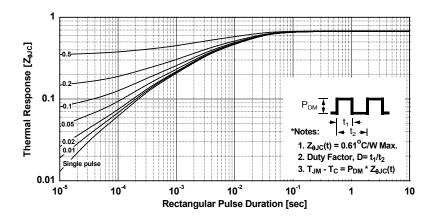
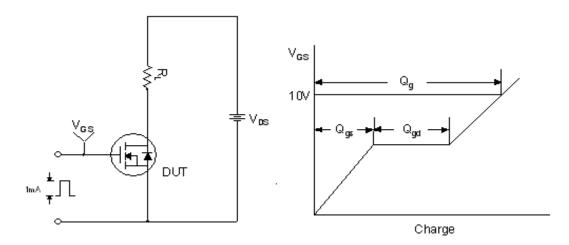


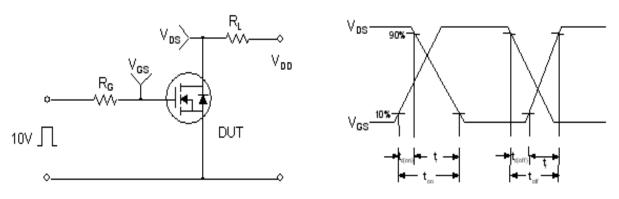
Figure 11. Transient Thermal Response Curve



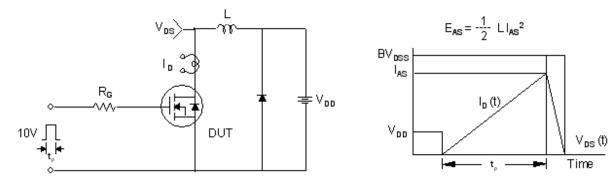
Gate Charge Test Circuit & Waveform



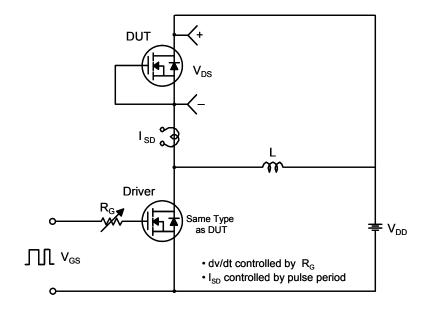
Resistive Switching Test Circuit & Waveforms

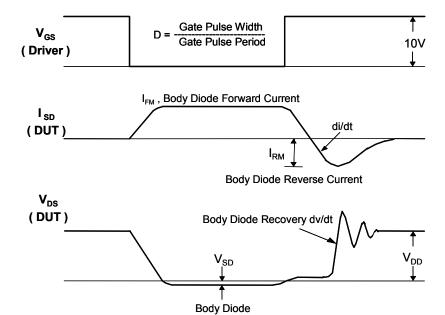


Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms

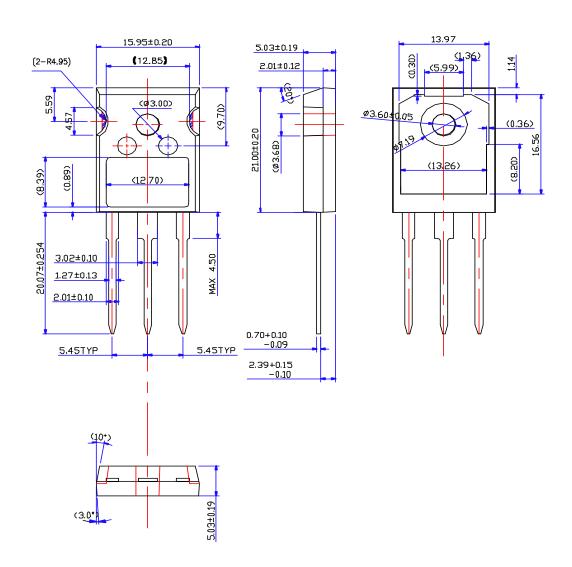




Forward Voltage Drop



TO-247-3L



Dimensions in Millimeters





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